

Notice of References Cited	Application/Control No. 10/823,673	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0141391	06-2005	Ueyama et al.	369/112.1
	B	US-2005/0163018	07-2005	Yukawa, Hiroaki	369/112.05
	C	US-			
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	L	US-			
	M	US-			

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*	N	JP 2001-281432	10-2001	JP	Murakawa, Shinko	----/----
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NON-PATENT DOCUMENTS

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